PCN Number:		201	20141119000					PCN Date: 1		12/03/2014
<b>Title:</b> Qualification of ASE Shanghai as an alternate Assembly/Test Site for Selected devices in the TSSOP Package									ed devices in	
<b>Customer Contact:</b>		PCN	Manager		30-6037 <b>Dept</b>		Dept:		ality vices	
Proposed 1 <sup>st</sup> Ship Da		ite:	03/03/2015	Estin	Estimated Sample Avail			ility:	Prov Requ	ided upon Jest
Change Type:										
Assembly Site			Assembly Process			$\boxtimes$	Assembly Materials			
Design			Electrical Specification				Mechanical Specification			
			Packing/Shipping/Labeling [				Test Process			
Wafer Bump Site			Wafer Bump Material			Wafer Bump Process				
Wafer Fab Site			Wafer Fab Materials				Wafer Fab Process			
			Part number change							
PCN Details										

## **Description of Change:**

Texas Instruments is pleased to announce the qualification of ASE Shanghai (ASES) as an alternate Assembly and Test site for the devices listed below in Group 1 and TI Taiwan (TAI) as an additional Assembly site for the devices in Group 2. Group 2 devices will have identical BOMs between the 2 sites. For group 1, BOM differences are noted in the table below:

What	MLA	AP1	ASESH
Mold Compound	4206193	SID# 101325962	SID#EN2000508
Mound Compound	4042500	SID#101306338	SID#EY1000063

Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.

## **Reason for Change:**

Continuity of Supply

Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:						
Assembly Site						
Amkor Philippines	Assembly Site Origin (22L)	ASO: AKR				
TI Malaysia	Assembly Site Origin (22L)	ASO: MLA				
TI Taiwan	Assembly Site Origin (22L)	ASO: TAI				
ASE Shanghai	Assembly Site Origin (22L)	ASO: ASH				

Sample product shipping label (not actual product label)





(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483812

(2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

## **Topside Device marking:**

Assembly site code for AKR= 4

Assembly site code for MLA= K

Assembly site code for TAI= T

Assembly site code for ASH= A

## **Product Affected**

Qualification Group #1 Devices (ASESH assembly):

AM26C31IPWR	MAX3232IPWR	SN74HC125PWR	SN74HC32PWR
CD4066BPWR	SN74ACT08PWR	SN74HC138PWR	SN74HC595PWR
CD4069UBPWR	SN74AHCT125PWR	SN74HC14PWR	SN74HCT04PWR
CD4541BPWR	SN74HC00PWR	SN74HC164PWR	SN74HCT138PWR
CD74HC123PWR	SN74HC02PWR	SN74HC166PWR	SN74HCT14PWR
LM239PWR	SN74HC04PWR	SN74HC174PWR	SN74HCT32PWR
LM339APWR	SN74HC05PWR	SN74HC259PWR	SN74HCU04PWR
MAX232ECPWR	SN74HC08PWR		

## **Qualification Group #2 Devices (TAI assembly):**

DRV8833PWPR DRV8833PWP

### **Qualification Group #1 Data:**

Qualification Report

MAX232ECPWR Qual (ASESH 14 and 16 pins TSSOP Offload) Approved 09/22/2014

### Product Attributes

Attributes	Qual Device: MAX232ECPWR	QBS Package: RC4558PWR	QBS Package: SN74LV14APWR	QBS Package: SN74LVC14APWR	QBS Package: ULN2003APW	QBS Package: LMV324IPWR	QBS Package: SN74AHC595PWR	QBS Package: SN74CBT3306PWR	QBS Package: SN74CBTLV3245APWR
Assembly Site	ASESH	ASE SHANGHAI	ASESH	ASE-SH	ASESH	ASE SHANGHAI	ASE SHANGHAI	ASE SHANGHAI	ASE SHANGHAI
Package Family	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP	TSSOP
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	DFAB	SFAB	SFAB	FFAB	SFAB	FFAB	SFAB	SFAB	FFAB
Wafer Fab Process	LBC3S	JI-SLM	EPIC1-S_SLM	P-9750 TLM	JI-SLM	BCB	EPIC1S DLM	50C24X2	ASL3C

QBS: Qual By Similarity
 Qual Device MAX232ECPWR is qualified at LEVEL1-260C

#### Qualification Results

Type	Test Name / Condition	Duration	QBS Package: RC4558PWR	QBS Package: SN74LV14APWR	QBS Package: SN74LVC14APWR	QBS Package: ULN2003APW	QBS Package: LMV324IPWR	QBS Package: SN74AHC595PWR	QBS Package: SN74CBT3306PWR	QBS Package: SN74CBTLV3245APW
HAST	Biased HAST, 130C/85%RH	96 Hours	1/77/0	1/77/0	1/77/0	1/77/0	2/158/0	1/77/0	1/77/0	1/77/0
тнв	Temperature Humidity Bias 85C/85%RH	1000 Cycles	-		-	-	-	-	-	-
AC	Autoclave 121C	96 Hours	-	-		-				
UHAST	Unbiased HAST 130C/85%RH	96 Hours	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0
TC	Temperature Cycle, - 65/150C	500 Cycles	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0	1/77/0
HTSL	High Temp. Storage Bake 170C	420 Hours	-	-	-	-	1/77/0	1/77/0	1/77/0	1/77/0
HTSL	High Temp. Storage Bake 150C	1000 Hours	1/77/0	1/77/0	1/77/0	1/77/0	-	-	-	-
HTOL	Life Test, 150C	300 hours	1/77/0	1/77/0	1/77/0	1/77/0	2/164/0	1/77/0	1/77/0	1/77/0
WBS	Ball Bond Shear	Wires	-	-	-	-	-	-	-	-
WBP	Bond Pull	Wires	-	-	-	-	-	-	-	-
PD	Physical Dimensions		-		-	-	-			
HBM	ESD - HBM	1000 V	-		-	-	-			
CDM	ESD - CDM	250 V	-	-		-	-		-	
LU	CMOS Latchup	(per JESD78 class II)	-	-	-	-	-	-	-	-
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass	Pass	Pass	Pass	Pass	Pass
	Bond Strength	Wires	1/76/0	1/76/0	1/76/0	1/76/0	2/160/0	1/77/0	1/77/0	1/77/0
- Preco - The f - The f - The f Quality Green	Bond Strength onditioning was performe following are equivalent F following are equivalent F	Wires ad for Autoclave, HTOL options base HTSL options base emp Cycle option a is available at Ti	1/76/0 Unbiased HAST, THE ed on an activation e ed on an activation e ns per JESD47: -550	1/76/0 B/Biased HAST, Tempera energy of 0.7eV : 125C/1i nergy of 0.7eV : 150C/1i C/125C/700 Cycles and -	1/76/0 ture Cycle, Thermal Shock k Hours, 140C/480 Hours, k Hours, and 170C/420 Ho	1/76/0 , and HTSL, as applic 150C/300 Hours, and	2/160/0 able			

Texas Instruments, Inc.

PCN#20141119000

# **Qualification Group #2 Data:**

Reference Qualification Data: Approved April 2012							
This qualification has been specifically developed for the validation of this change. The qualification data							
validates that the proposed change meets the applicable released technical specifications.							
Qualificat	ion Device: DRV88		C)				
	Package Constru	ction Details					
Assembly Site:	TAI A/T	Mold Compound:	4205443				
# Pins-Designator, Family:	28-PWP, TSSOP	Mount Compound:	4208458				
Lead Frame Material/Finish:	Cu, NiPdAu	Bond Wire:	1.3 Mil Dia., Cu				
Qualification:  Plan  Test Results							
Reliability Test	Conditions	Sample Size / Fail					
Electrical Characterization	Per Datasheet Lim	Pass					
**Autoclave 121C	121C, 2 atm (96 H	77/0					
**T/C -65C/150C	-65C/+150C (500	77/0					
ESD HBM	500V, 1000V, 150	3/0					
ESD CDM	200V, 500V	3/0					
Latch-up	(per JESD78)	(per JESD78)					
Notes: **Tests require preconditioning sequence: MSL1-260C							

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
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